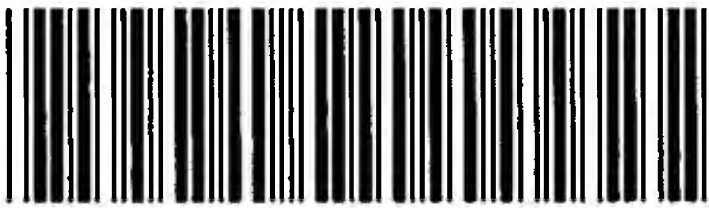


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/605,517	LIEN, CHI-CHIN	
	Examiner	Art Unit	
	Jean W. Désir	2622	

SEARCHED			
Class	Subclass	Date	Examiner
348	452 448 451	8/17/2007	JWD
	441, 715		
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	430.1		
	431.1		
375	240.01		
	240.26		
382	236, 233		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	8/17/2007	JWD